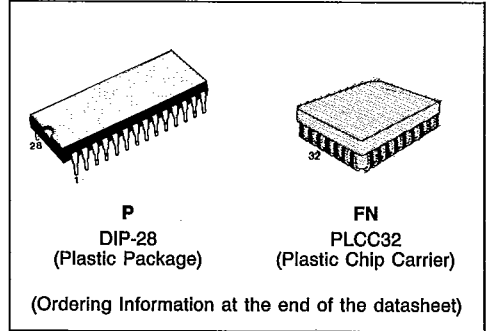


64K (8K x 8) CMOS ONE TIME PROGRAMMABLE ROM

- COMPATIBLE TO TS27C64A EPROM (ELECTRICAL PARAMETERS, PROGRAMMING)
- PROGRAMMING VOLTAGE 12.5V
- HIGH SPEED PROGRAMMING
- 28-PIN JEDEC APPROVED PIN-OUT
- 32-PIN JEDEC APPROVED PIN-OUT (PLCC)
- IDEAL FOR AUTOMATIC INSERTION



DESCRIPTION

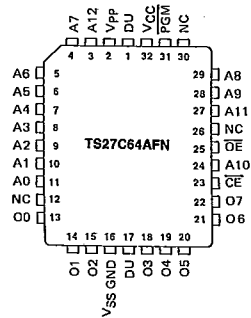
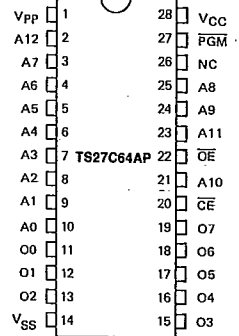
The TS27C64AP and TS27C64AFN are high speed 65,536-bit One Time Programmable (OTP) CMOS ROM ideally suited for applications where fast turn-around is an important requirement.

The TS27C64AP is packaged in a 28-pin dual-in-line plastic package, the TS27C64AFN in a 32-pin PLCC plastic package and therefore can not be rewritten. Programming is performed according to standard SGS-THOMSON 64K EPROM procedure.

PIN NAMES

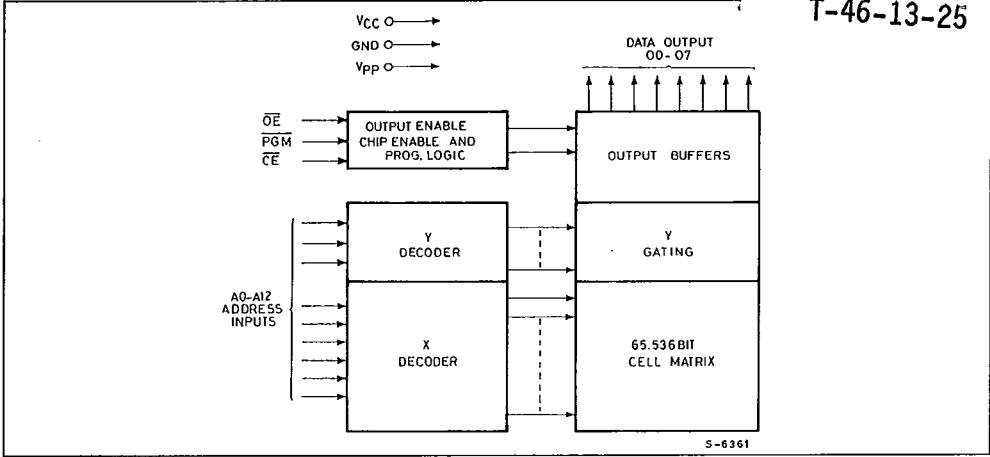
| | |
|--------------------------------|---------------|
| A0—A12 | ADDRESS |
| CE | CHIP ENABLE |
| OE | OUTPUT ENABLE |
| O ₀ —O ₇ | OUTPUTS |
| PGM | PROGRAM |
| NC | NON CONNECTED |
| DU | DO NOT USE |

PIN CONNECTIONS



BLOCK DIAGRAM

T-46-13-25



ABSOLUTE MAXIMUM RATINGS⁽¹⁾

| Symbol | Parameter | Value | Unit |
|--------------------------------|---|----------------------------------|------|
| T _{amb} | Operating temperature range TS27C64A-C TS27C64A-V TS27C64A-T | T _L to T _H | °C |
| | | 0 to +70 | |
| | | -40 to +85 | |
| | | -40 to +105 | |
| T _{stg} | Storage temperature range | -65 to +125 | °C |
| V _{PP} ⁽²⁾ | Supply voltage | -0.6 to +14 | V |
| V _{IN} ⁽²⁾ | Input voltages Except V _{PP} , A9 | A9 | V |
| | | A9 | |
| P _D | Max power dissipation | 1.5 | W |
| | Lead temperature (Soldering: 10 seconds) | +300 | °C |

Notes: 1. "Maximum ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating temperature range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical characteristics" provides conditions for actual device operation.
2. With respect to GND

OPERATING MODES

| MODE | PINS | \overline{CE} | \overline{OE} | A9 | \overline{PGM} | V _{PP} | V _{CC} | OUTPUTS |
|-------------------------------------|------|-----------------|-----------------|-------------------------------|------------------|-----------------|-----------------|------------------|
| READ | | V _{IL} | V _{IL} | X | V _{IH} | V _{CC} | V _{CC} | D _{OUT} |
| OUTPUT DISABLE | | V _{IL} | V _{IH} | X | V _{IH} | V _{CC} | V _{CC} | Hi-Z |
| STANDBY | | V _{IH} | X | X | X | V _{CC} | V _{CC} | Hi-Z |
| HIGH SPEED PROGRAMMING | | V _{IL} | V _{IH} | X | V _{IL} | V _{PP} | V _{CC} | D _{IN} |
| PROGRAM VERIFY | | V _{IL} | V _{IL} | X | V _{IH} | V _{PP} | V _{CC} | D _{OUT} |
| PROGRAM INHIBIT | | V _{IH} | X | X | X | V _{PP} | V _{CC} | Hi-Z |
| ELECTRONIC SIGNATURE ⁽³⁾ | | V _{IL} | V _{IL} | V _H ⁽²⁾ | V _{IH} | V _{CC} | V _{CC} | CODE |

Notes: 1. X can be either V_{IL} or V_{IH} — 2. V_H = 12.0V ± 0.5V
3. All address lines at V_{IL} except A9 and A0 that is toggled from V_{IL} (manufacturer code: 9B) to V_{IH} (type code: 08).

READ OPERATION

S G S-THOMSON

30E D

DC CHARACTERISTICS ($T_{amb} = T_L$ to T_H , $V_{CC} = 5V \pm 10\%$, $GND = 0V$; Unless otherwise specified)

| Symbol | Parameter | Test Conditions | Values | | | Unit |
|-------------|--|---|-----------------------|---------------------|--------------|---------|
| | | | Min. | Typ. ⁽¹⁾ | Max. | |
| I_{LI} | Input Load Current | $V_{IN} = V_{CC}$ or GND | | | 10 | μA |
| I_{LO} | Output Leakage Current | $V_{OUT} = V_{CC}$ or GND, $\overline{CE} = V_{IH}$ | | | 10 | μA |
| V_{PP} | V_{PP} Read Voltage | | $V_{CC} - 0.7$ | | V_{CC} | V |
| V_{IL} | Input Low Voltage | | -0.1 | | 0.8 | V |
| V_{IH} | Input High Voltage | | 2.0 | | $V_{CC} + 1$ | V |
| V_{OL} | Output Low Voltage | $I_{OL} = 2.1$ mA $I_{OL} = 0$ μA | | | 0.45 0.1 | V |
| V_{OH} | Output High Voltage | $I_{OH} = -400$ μA $I_{OH} = 0$ μA | 2.4 $V_{CC} - 0.1$ | | | V |
| I_{CC2} | V_{CC} Supply Active Current TTL Levels | $\overline{CE} = \overline{OE} = V_{IL}$, Inputs = V_{IH} or V_{IL} , $f = 5$ MHz, $I/O = 0$ mA | | 10 | 30 | mA |
| I_{CCSB1} | V_{CC} Supply Standby Current | $\overline{CE} = V_{IH}$ | | 0.5 | 1 | mA |
| I_{CCSB2} | V_{CC} Supply Standby Current | $\overline{CE} = V_{CC}$ | | 10 | 100 | μA |
| I_{PP1} | V_{PP} Read Current | $V_{PP} = V_{CC} = 5.5V$ | | | 100 | μA |

Note: 1. Typical conditions are for operation at: $T_{amb} = +25^\circ C$, $V_{CC} = 5V$, $V_{PP} = V_{CC}$, and $V_{SS} = 0V$ AC CHARACTERISTICS⁽¹⁾ ($T_{amb} = T_L$ to T_H)

| Symbol | Parameter | Test Conditions | 27C64A -15 | | 27C64A -20 | | 27C64A -25 | | 27C64A -30 | | Unit |
|---------------|---|--|---------------|-----|---------------|-----|---------------|-----|---------------|-----|------|
| | | | Min | Max | Min | Max | Min | Max | Min | Max | |
| t_{ACC} | Address to Output Delay | $\overline{CE} = \overline{OE} = V_{IL}$ | | 150 | | 200 | | 250 | | 300 | ns |
| t_{CE} | \overline{CE} to Output Delay | $\overline{OE} = V_{IL}$ | | 150 | | 200 | | 250 | | 300 | ns |
| t_{OE} | Output Enable to Output Delay | $\overline{CE} = V_{IL}$ | | 75 | | 80 | | 100 | | 120 | ns |
| $t_{DF(2,4)}$ | \overline{OE} or \overline{CE} High to | $\overline{CE} = V_{IL}$ | 0 | 50 | 0 | 50 | 0 | 60 | 0 | 105 | ns |
| t_{OH} | Output Hold from addresses, \overline{CE} or \overline{OE} whichever occurred first | $\overline{CE} = \overline{OE} = V_{IL}$ | 0 | | 0 | | 0 | | 0 | | ns |

CAPACITANCE $T_{amb} = +25^\circ C$, $f = 1$ MHz (Note 3)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|-----------|--------------------|-----------------|------|------|------|------|
| C_{in} | Input Capacitance | $V_{IN} = 0V$ | | 4 | 6 | pF |
| C_{out} | Output Capacitance | $V_{OUT} = 0V$ | | 8 | 12 | pF |

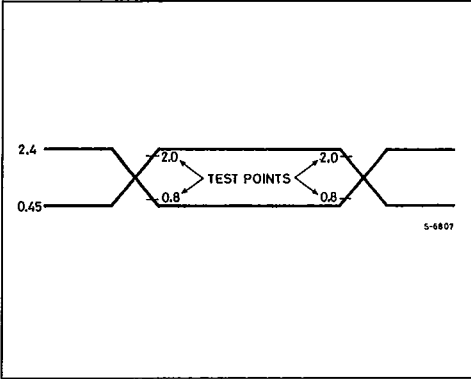
- Notes: 1. V_{CC} must be applied at the same time or before V_{pp} and removed after or at the same time as V_{pp} . V_{pp} may be connected to V_{CC} except during program.
2. The t_{DF} compare level is determined as follows:
High to THREE-STATE, the measured $V_{OH(DC)} - 0.1V$
Low to THREE-STATE the measured $V_{OL(DC)} + 0.1V$.
3. Capacitance is guaranteed by periodic testing. $T_{amb} = +25^\circ C$, $f = 1$ MHz.
4. t_{DF} is specified from OE or CE whichever occurs first. This parameter is only sampled and not 100% tested.

AC TEST CONDITIONS

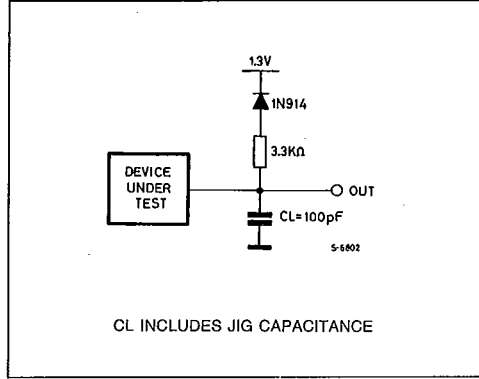
Output Load: 1 TTL gate and $CL = 100\text{ pF}$
 Input Rise and Fall Times $\leq 20\text{ ns}$
 Input pulse levels: 0.45V to 2.4V
 Timing Measurement Reference Level
 Inputs, Outputs 0.8V and 2V

T-46-13-25

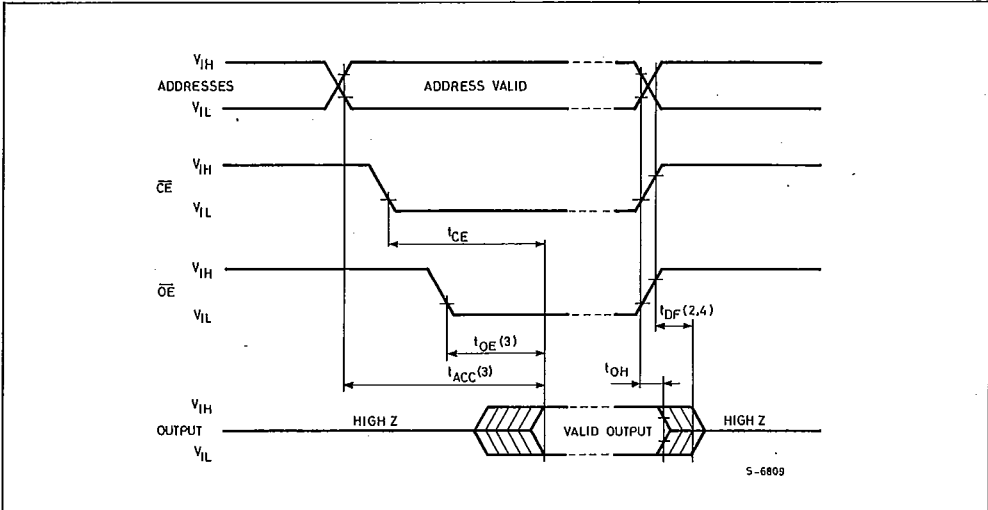
AC TESTING INPUT/OUTPUT WAVEFORM



AC TESTING LOAD CIRCUIT



AC WAVEFORMS



Notes:

1. Typical values are for $T_{amb} = 25^\circ\text{C}$ and nominal supply voltage
2. This parameter is only sampled and not 100% tested.
3. OE may be delayed up to $t_{ACC} - t_{OE}$ after the falling edge CE without impact on t_{ACC}
4. t_{DF} is specified from OE or CE whichever occurs first.

SGS-THOMSON

DEVICE OPERATION

The seven modes of operation of the TS27C64A are listed in the Operating Modes table. A single 5V power supply is required in the read mode. All inputs are TTL levels except for V_{pp} .

READ MODE

The TS27C64A has two control functions, both of which must be logically active in order to obtain data at the outputs. Chip Enable (CE) is the power control and should be used for device selection. Output Enable (OE) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from CE to Output (t_{CE}). Data is available at the outputs after a delay of t_{OE} from the falling edge of OE, assuming that CE has been low and addresses have been stable for at least $t_{ACC} - t_{OE}$.

STANDBY MODE

The TS27C64A has a standby mode which reduces the maximum power dissipation to 5.5 mW. The TS27C64A is placed in the standby mode by applying a TTL high signal to the CE input. When in standby mode, the outputs are in a high impedance state, independent of the OE input.

OUTPUT OR-TYING

Because OTPs are usually used in larger memory arrays, we have provided two control lines which accommodate this multiple memory connection. The two control lines allow for:

- the lowest possible memory power dissipation, and
- complete assurance that output bus contention will not occur.

To use these control lines most efficiently, \overline{CE} should be decoded and used as the primary device selecting function, while OE should be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low power standby modes and that the output pins are active only when data is desired from a particular memory device.

PROGRAMMING

Caution: Exceeding 14V on V_{pp} pin will damage the TS27C64A.

Initially, all bits of the TS27C64A are in the "1" state. Data is introduced by selectively programming "0s" into the desired bit locations. Although only "0s" will be programmed, both "1s" and "0s" can be presented in the data word.

3OE D

The TS27C64A is in the programming mode when the V_{pp} input is at 12.5 V and CE and PGM are both at TTL Low. It is required that a 0.1 μ F capacitor be placed across V_{pp} , V_{CC} and ground to suppress spurious voltage transients which may damage the device. The data to be programmed is applied 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL.

Programming of multiple TS27C64As in parallel with the same data can be easily accomplished due to the simplicity of the programming requirements. Like inputs of the parallel TS27C64As may be connected together when they are programmed with the same data. A low level TTL pulse applied to the PGM input programs the paralleled TS27C64As.

HIGH SPEED PROGRAMMING

The high speed programming algorithm described in the flow chart rapidly programs TS27C64A using an efficient and reliable method particularly suited to the production programming environment. Typical programming times for individual devices are on the order of 1 minute.

PROGRAM INHIBIT

Programming of multiple TS27C64As in parallel with different data is also easily accomplished by using the program inhibit mode. A high level on CE or PGM inputs inhibits the other TS27C64As from being programmed. Except for CE, all like inputs (including OE) of the parallel TS27C64As may be common. A TTL low-level pulse applied to a TS27C64A CE and PGM inputs with V_{pp} at 12.5 V will program that TS27C64A.

PROGRAM VERIFY

A verify may be performed on the programmed bits to determine that they were correctly programmed. The verify is performed with CE and OE at V_{IL} , PGM at V_{IH} and V_{pp} at 12.5 V.

ELECTRONIC SIGNATURE MODE

Electronic signature mode allows the reading out of a binary code that will identify the EPROM manufacturer and type. This mode is intended for use by programming equipment for the purpose of automatically matching the device to be programmed with its corresponding programming algorithm. This mode is functional in the $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ ambient temperature range that is required when programming the TS27C64A. To activate this mode the programming equipment must force 11.5V to 12.5V on address line A9 of the TS27C64A. Two bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH} . All other address lines must be held at V_{IL} during electronic signature mode.

PROGRAMMING OPERATIONS⁽¹⁾($T_{amb} = 25 \pm 5^\circ\text{C}$, $V_{CC} = 6.0\text{V} \pm 0.25\text{V}$, $V_{PP} = 12.5\text{V} \pm 0.3\text{V}$)

DC AND OPERATING CHARACTERISTICS

T-46-13-25

| Symbol | Parameter | Test Conditions | Values | | | Unit |
|-----------|--|---|--------|------|--------------|---------------|
| | | | Min. | Typ. | Max. | |
| I_I | Input Current (all inputs) | $V_I = V_{IL}$ or V_{IH} | | | 10 | μA |
| V_{IL} | Input Low Level (all inputs) | | -0.1 | | 0.8 | V |
| V_{IH} | Input High Level | | 2.0 | | $V_{CC} + 1$ | V |
| V_{OL} | Output low voltage during verify | $I_{OL} = 2.1 \text{ mA}$ | | | 0.45 | V |
| V_{OH} | Output high voltage during verify | $I_{OH} = -400 \mu\text{A}$ | 2.4 | | | V |
| I_{CC3} | V_{CC} Supply current (Program & Verify) | | | | 30 | mA |
| I_{PP2} | V_{PP} supply current (Program) | $\overline{CE} = V_{IL} = \overline{PGM}$ | | | 30 | mA |

S G S - THOMSON

30E D

AC CHARACTERISTICS

| Symbol | Parameter | Test Conditions | Values | | | Unit |
|-----------------|--|-----------------|--------|------|-------|---------------|
| | | | Min. | Typ. | Max. | |
| t_{AS} | Address Set-up Time | | 2 | | | μs |
| t_{OES} | \overline{OE} Set-up Time | | 2 | | | μs |
| t_{DS} | Data Set-up Time | | 2 | | | μs |
| t_{AH} | Address Hold Time | | 0 | | | μs |
| t_{DH} | Data Hold Time | | 2 | | | μs |
| t_{DFP} | Output enable to output float delay | | 0 | | 130 | ns |
| t_{VPS} | V_{PP} set-up time | | 2 | | | μs |
| t_{VCS} | V_{CC} set-up time | | 2 | | | μs |
| t_{PW} | \overline{PGM} initial program pulse width | | 0.95 | 1.0 | 1.05 | ms |
| $t_{OPW}^{(2)}$ | \overline{PGM} overprogram pulse width | | 2.85 | | 78.75 | ms |
| t_{CES} | \overline{CE} set-up time | | 2 | | | μs |
| t_{OE} | Data valid from \overline{OE} | | | | 150 | ns |

Notes: 1. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP} .
 2. t_{OPW} is defined in flow chart.

AC TEST CONDITIONS

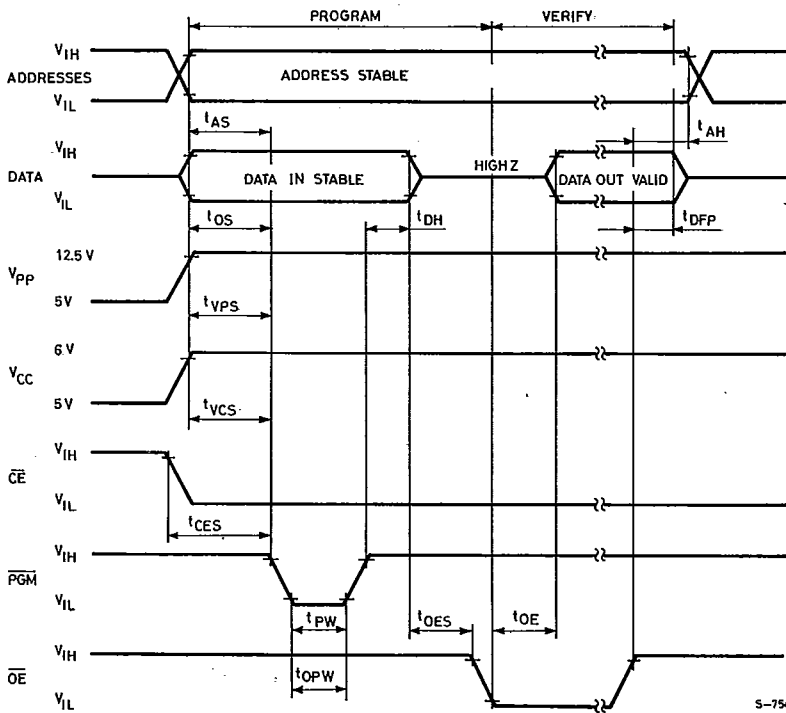
Input rise and fall times (10% to 90%) 20ns
 Input pulse levels 0.45V to 2.4V
 Input timing reference level 0.8V and 2.0V
 Output timing reference level 0.8V and 2.0V

HIGH SPEED PROGRAMMING WAVEFORMS

T-46-13-25

SGS-THOMSON

30E D

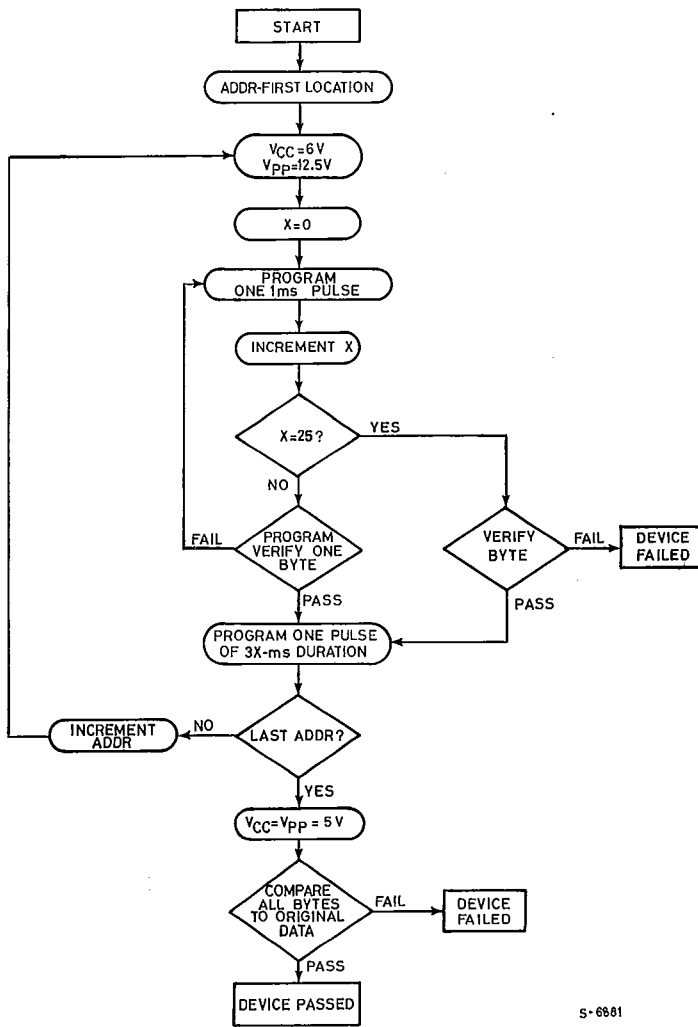


5-7543/2

1. The input timing reference level is 0.8V for V_{IL} and 2.0V for V_{IH}.
2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.
3. When programming the TS27C64A, a 0.1 μF capacitor is required across V_{pp} and ground to suppress spurious voltage transients which can damage the device.

HIGH SPEED PROGRAMMING FLOW CHART

T-46-13-25



S-6661

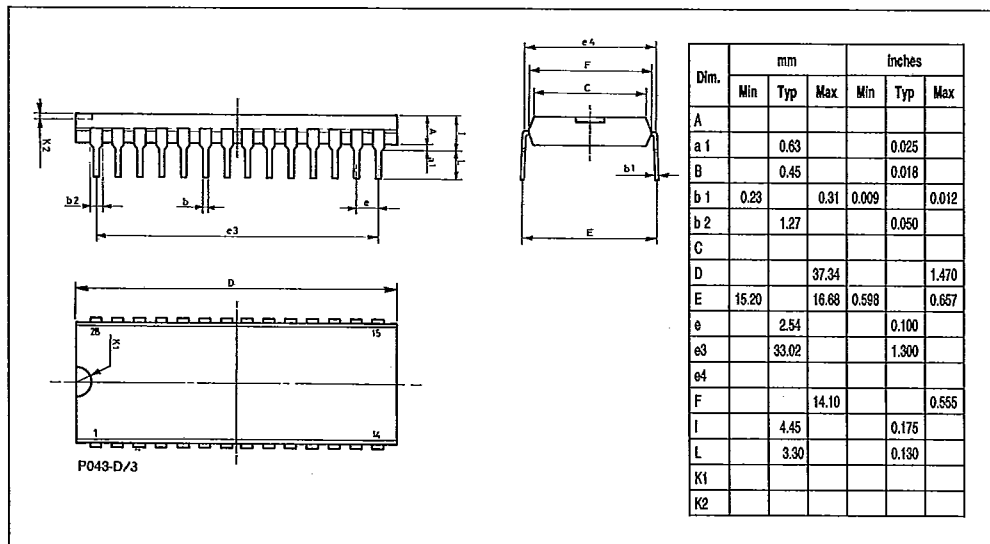
ORDERING INFORMATION (TS27C64AP); S G S-THOMSON

30E D

| Part Number | Access Time | Supply Voltage | Temp. Range | Package |
|---------------|-------------|----------------|----------------|---------|
| TS27C64A-15CP | 150 ns | 5V ± 10% | 0 to + 70°C | DIP-28 |
| TS27C64A-20CP | 200 ns | 5V ± 10% | 0 to + 70°C | DIP-28 |
| TS27C64A-25CP | 250 ns | 5V ± 10% | 0 to + 70°C | DIP-28 |
| TS27C64A-30CP | 300 ns | 5V ± 10% | 0 to + 70°C | DIP-28 |
| TS27C64A-15VP | 150 ns | 5V ± 10% | -40 to + 85°C | DIP-28 |
| TS27C64A-20VP | 200 ns | 5V ± 10% | -40 to + 85°C | DIP-28 |
| TS27C64A-25VP | 250 ns | 5V ± 10% | -40 to + 85°C | DIP-28 |
| TS27C64A-30VP | 300 ns | 5V ± 10% | -40 to + 85°C | DIP-28 |
| TS27C64A-15TP | 150 ns | 5V ± 10% | -40 to + 105°C | DIP-28 |
| TS27C64A-20TP | 200 ns | 5V ± 10% | -40 to + 105°C | DIP-28 |
| TS27C64A-25TP | 250 ns | 5V ± 10% | -40 to + 105°C | DIP-28 |
| TS27C64A-30TP | 300 ns | 5V ± 10% | -40 to + 105°C | DIP-28 |

PACKAGE MECHANICAL DATA

28-PIN PLASTIC DIP



ORDERING INFORMATION (TS27C64AFN)

| Part Number | Access Time | Supply Voltage | Temp. Range | Package |
|----------------|-------------|----------------|----------------|---------|
| TS27C64A-15CFN | 150 ns | 5V ± 10% | 0 to + 70°C | PLCC32 |
| TS27C64A-20CFN | 200 ns | 5V ± 10% | 0 to + 70°C | PLCC32 |
| TS27C64A-25CFN | 250 ns | 5V ± 10% | 0 to + 70°C | PLCC32 |
| TS27C64A-30CFN | 300 ns | 5V ± 10% | 0 to + 70°C | PLCC32 |
| TS27C64A-15VFN | 150 ns | 5V ± 10% | -40 to + 85°C | PLCC32 |
| TS27C64A-20VFN | 200 ns | 5V ± 10% | -40 to + 85°C | PLCC32 |
| TS27C64A-25VFN | 250 ns | 5V ± 10% | -40 to + 85°C | PLCC32 |
| TS27C64A-30VFN | 300 ns | 5V ± 10% | -40 to + 85°C | PLCC32 |
| TS27C64A-15TFN | 150 ns | 5V ± 10% | -40 to + 105°C | PLCC32 |
| TS27C64A-20TFN | 200 ns | 5V ± 10% | -40 to + 105°C | PLCC32 |
| TS27C64A-25TFN | 250 ns | 5V ± 10% | -40 to + 105°C | PLCC32 |
| TS27C64A-30TFN | 300 ns | 5V ± 10% | -40 to + 105°C | PLCC32 |

PACKAGE MECHANICAL DATA

PLCC32 32-LEAD PLASTIC LEADED CHIP CARRIER

